

Notice of References Cited	Application/Control No. 10/728,348	Applicant(s)/Patent Under Reexamination BURDINE ET AL.	
	Examiner Cynthia Britt	Art Unit 2138	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,278,956	08-2001	Leroux et al.	702/117
*	B	US-6,308,290	10-2001	Forlenza et al.	714/724
	C	US-			
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	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gate Level Fault Diagnosis in Scan Based BIST by Bayraktaroglu et al Proceedings of the 2002 Design automation and test in Europe Conference 1530-1591/02 IEEE
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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